



ALPHA & OMEGA
SEMICONDUCTOR

AO3160E

600V, 0.04A N-Channel MOSFET

General Description

- Logic Level Driving 4.5V
- ESD Protection
- RoHS and Halogen Free Compliant

Product Summary

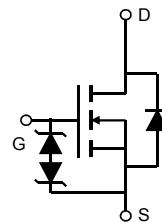
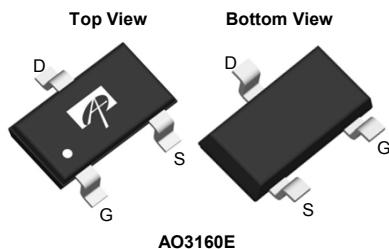
| | |
|----------------------------------|--------|
| V_{DS} @ $T_{j,max}$ | 700V |
| I_D (at $V_{GS}=10V$) | 0.04A |
| $R_{DS(ON)}$ (at $V_{GS}=10V$) | < 500Ω |
| $R_{DS(ON)}$ (at $V_{GS}=4.5V$) | < 600Ω |

Applications

- Load Switch

Typical ESD protection

HBM Class 2



| Orderable Part Number | Package Type | Form | Minimum Order Quantity |
|-----------------------|--------------|-------------|------------------------|
| AO3160E | SOT23A | Tape & Reel | 3000 |

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

| Parameter | Symbol | Maximum | Units |
|--|----------------|------------|---------------------|
| Drain-Source Voltage | V_{DS} | 600 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Continuous Drain Current ^{A,F} | I_D | 0.04 | A |
| $T_A=70^\circ\text{C}$ | | 0.03 | |
| Pulsed Drain Current ^B | I_{DM} | 0.12 | |
| Peak diode recovery dv/dt | dv/dt | 5 | V/ns |
| Power Dissipation ^A | P_D | 1.39 | W |
| $T_A=70^\circ\text{C}$ | | 0.89 | W/ $^\circ\text{C}$ |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 150 | $^\circ\text{C}$ |
| Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds | T_L | 300 | $^\circ\text{C}$ |

Thermal Characteristics

| Parameter | Symbol | Typical | Maximum | Units |
|--|-----------------|---------|---------|---------------------------|
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 70 | 90 | $^\circ\text{C}/\text{W}$ |
| Steady-State | | 100 | 125 | $^\circ\text{C}/\text{W}$ |
| Maximum Junction-to-Lead ^C | $R_{\theta JL}$ | 63 | 80 | $^\circ\text{C}/\text{W}$ |

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|----------------------------------|--|--|-----|-------|------|-------|
| STATIC PARAMETERS | | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | I _D =250μA, V _{GS} =0V, T _J =25°C | 600 | - | - | V |
| | | I _D =250μA, V _{GS} =0V, T _J =150°C | - | 700 | - | |
| BV _{DSS} / ΔT_J | Breakdown Voltage Temperature Coefficient | I _D =250μA, V _{GS} =0V | - | 0.68 | - | V/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} =600V, V _{GS} =0V | - | - | 1 | μA |
| | | V _{DS} =480V, T _J =125°C | - | - | 10 | |
| I _{GSS} | Gate-Body leakage current | V _{DS} =0V, V _{GS} =±20V | - | - | ±10 | μA |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} =5V, I _D =8μA | 1.4 | 2 | 3.2 | V |
| R _{DS(ON)} | Static Drain-Source On-Resistance | V _{GS} =10V, I _D =0.016A | - | 176 | 500 | Ω |
| | | V _{GS} =4.5V, I _D =0.016A | - | 178 | 600 | Ω |
| g _{Fs} | Forward Transconductance | V _{DS} =40V, I _D =0.016A | - | 0.125 | - | S |
| V _{SD} | Diode Forward Voltage | I _S =0.016A, V _{GS} =0V | - | 0.76 | 1 | V |
| I _S | Maximum Body-Diode Continuous Current | | - | - | 0.04 | A |
| I _{SM} | Maximum Body-Diode Pulsed Current ^c | | - | - | 0.12 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C _{iss} | Input Capacitance | V _{GS} =0V, V _{DS} =25V, f=1MHz | - | 9.5 | - | pF |
| C _{oss} | Output Capacitance | | - | 1.7 | - | pF |
| C _{rss} | Reverse Transfer Capacitance | V _{GS} =0V, V _{DS} =25V, f=1MHz | - | 0.6 | - | pF |
| R _g | Gate resistance | f=1MHz | - | 20 | - | Ω |
| SWITCHING PARAMETERS | | | | | | |
| Q _g | Total Gate Charge | V _{GS} =10V, V _{DS} =400V, I _D =0.01A | - | 0.9 | - | nC |
| Q _{gs} | Gate Source Charge | | - | 0.09 | - | nC |
| Q _{gd} | Gate Drain Charge | | - | 0.49 | - | nC |
| T _{d(on)} | Turn-On Delay Time | V _{GS} =10V, V _{DS} =300V, I _D =0.01A, R _G =6Ω | - | 4 | - | ns |
| T _r | Turn-On Rise Time | | - | 5 | - | ns |
| T _{d(off)} | Turn-Off Delay Time | | - | 13 | - | ns |
| T _f | Turn-Off Fall Time | | - | 55 | - | ns |
| T _{rr} | Body Diode Reverse Recovery Time | I _F =0.016A, dI/dt=100A/μs, V _{DS} =300V | - | 105 | - | ns |
| Q _{rr} | Body Diode Reverse Recovery Charge | | - | 9.5 | - | nC |

A. The value of R_{qJA} is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C. The value in any given application depends on the user's specific board design.

B. Repetitive rating, pulse width limited by junction temperature.

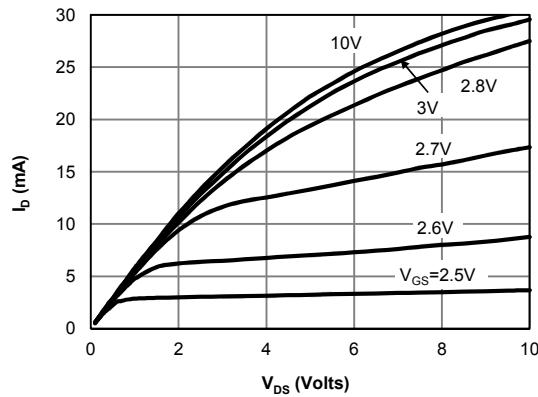
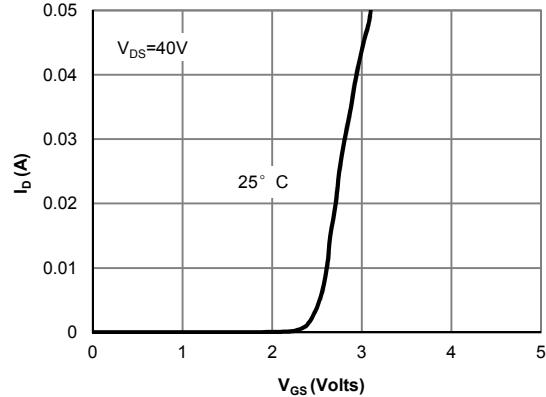
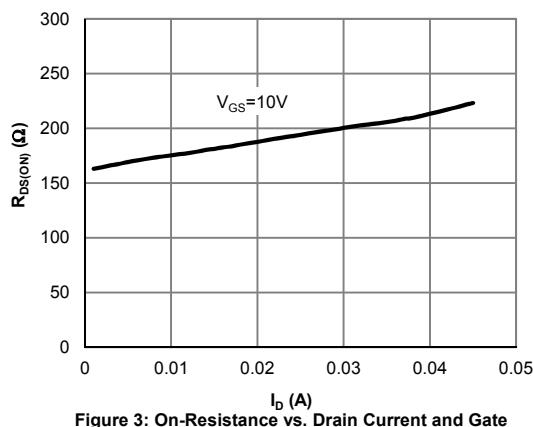
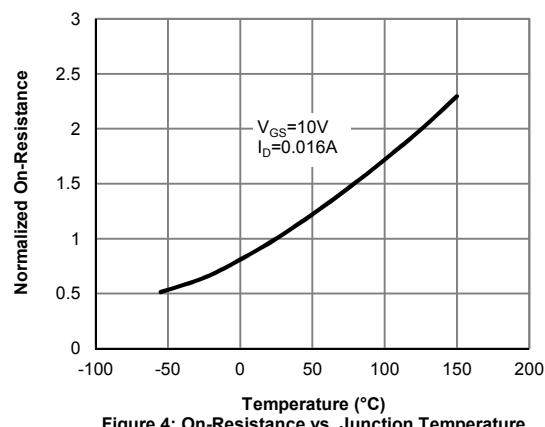
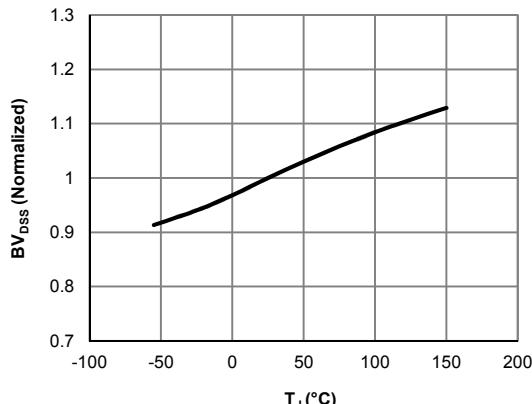
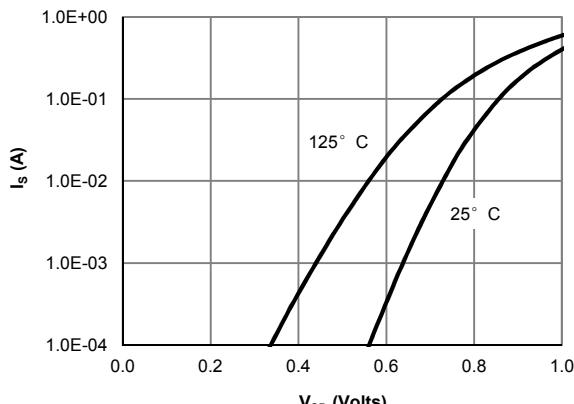
C. The R_{qJA} is the sum of the thermal impedance from junction to lead R_{qUL} and lead to ambient.

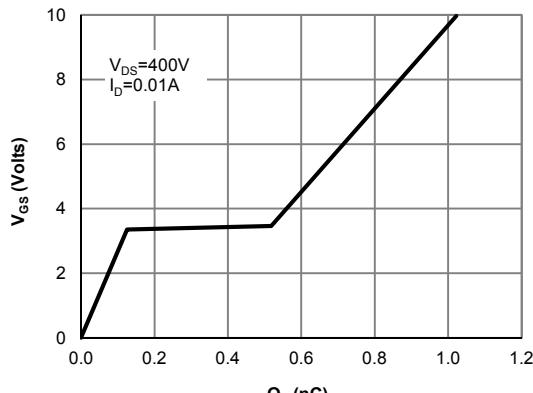
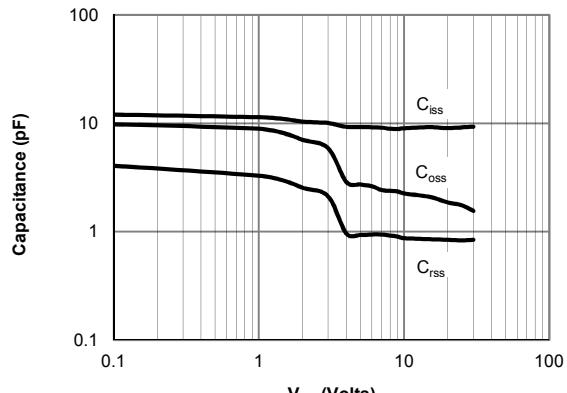
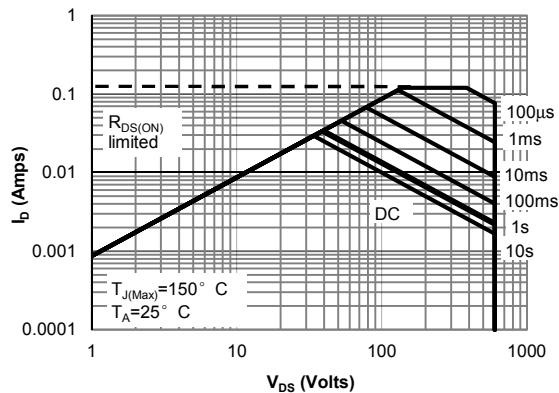
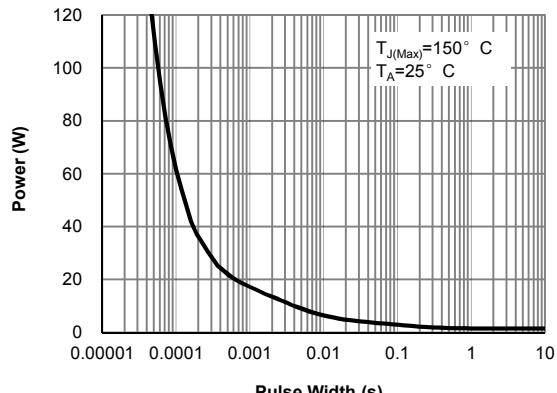
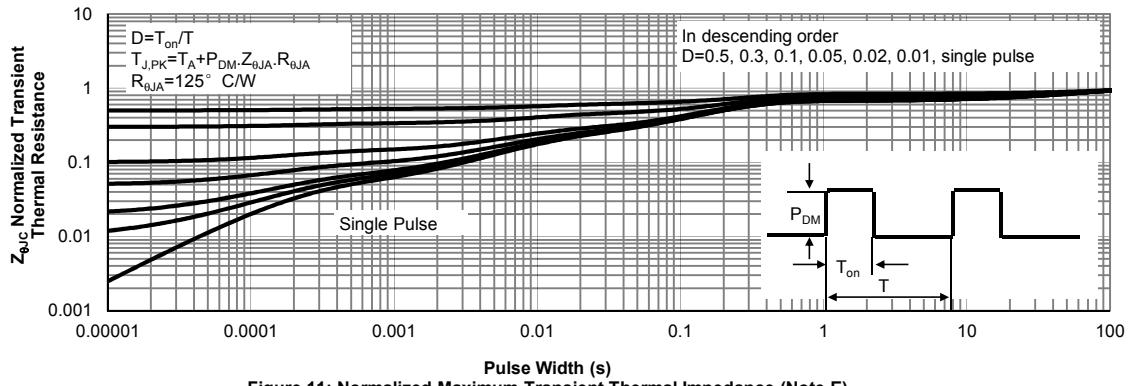
D. The static characteristics in Figures 1 to 6 are obtained using <300 ms pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C. The SOA curve provides a single pulse rating.

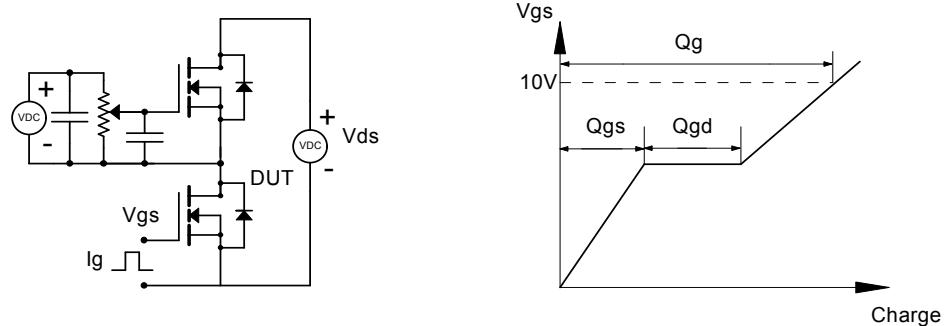
F. The current rating is based on the t ≤ 10s thermal resistance rating.

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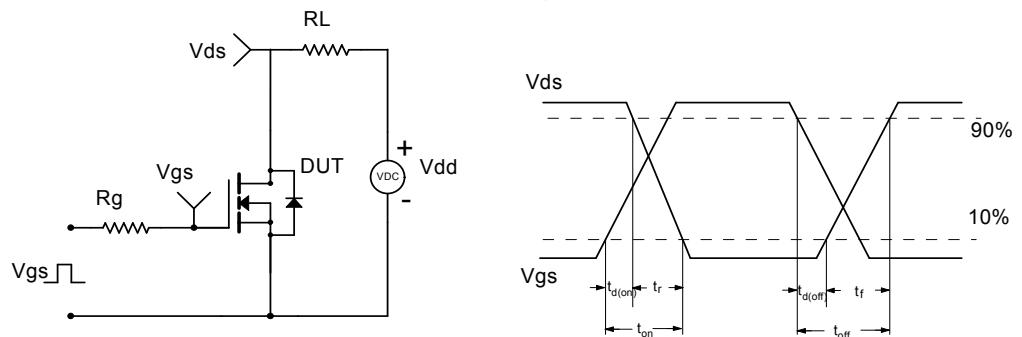
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics

Figure 2: Transfer Characteristics

Figure 3: On-Resistance vs. Drain Current and Gate Voltage

Figure 4: On-Resistance vs. Junction Temperature

Figure 5: Break Down vs. Junction Temperature

Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)

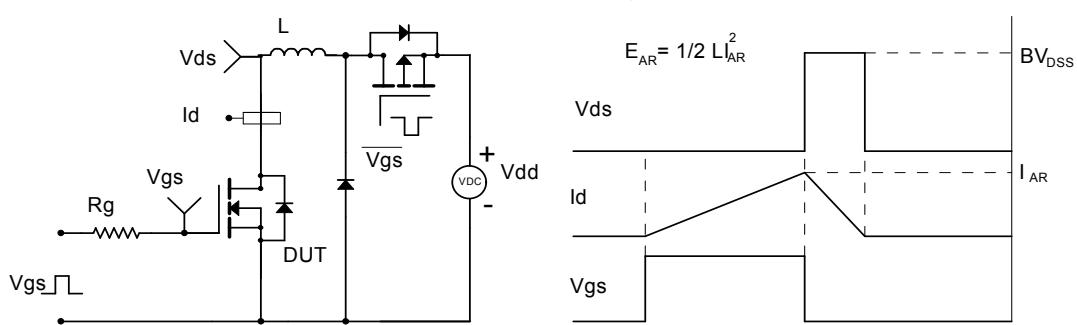
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

